

<b>Notice of References Cited</b>	Application/Control No. 10/588,154		Applicant(s)/Patent Under Reexamination SUGIYAMA ET AL.	
	Examiner John R. Lee		Art Unit 2878	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0008422 A1	07-2001	Mizuno et al.	348/302
*	B	US-2002/0085104 A1	07-2002	Mizuno et al.	348/294
*	C	US-6,455,837 B2	09-2002	Mizuno, Seiichiro	250/214R
*	D	US-2002/0190193 A1	12-2002	Mizuno et al.	250/214.00R
*	E	US-2005/0041124 A1	02-2005	Sugiyama et al.	348/294
*	F	US-2006/0261245 A1	11-2006	Sugiyama et al.	250/208.1
*	G	US-2006/0273238 A1	12-2006	Sugiyama et al.	250/208.1
*	H	US-7,193,197 B2	03-2007	Sugiyama et al.	250/208.1
*	I	US-2009/0014627 A1	01-2009	Sugiyama et al.	250/208.1
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003189181 A	07-2003	Japan	SUGIYAMA et al.	H04N 05/335
	O	EP 1460839 A1	09-2004	European Patent	SUGIYAMA et al.	H04N 05/335
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.